

N-Channel Depletion Mode Combo MOSFET Module

General Description

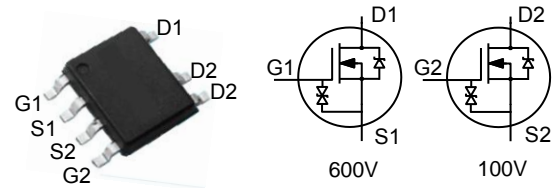
DME6010D integrates a 600V depletion mode MOSFET as a startup device and a 100V depletion mode MOSFET with patented UltraVt[®], which will provide stable and safe voltage for load as a non-isolated high voltage regulator. DME6010D is used in PD charger or QC charger for the cost down and space saving purpose.

No.	BV _{DSS}	R _{DS(ON)} (Max.)	I _{DSS} (Min)
1	600V	700 Ω	5mA
2	100V	30 Ω	100mA

General Features

- Proprietary Advanced Planar Technology
- Rugged Polysilicon Gate Cell Structure
- Proprietary Advanced High V_{th} Technology
- RoHS Compliant
- Halogen-free available

SOP-7



Applications

- PD / Quick Charger
- SMPS Start-up Circuit

Ordering Information

Part Number	Package	Marking	Remark
DME6010D	SOP-7	6010D	Halogen Free

Absolute Maximum Ratings

T_A=25°C unless otherwise specified

Symbol	Parameter	600V MOSFET	100V MOSFET	Unit
V _{DSX}	Drain-to-Source Voltage ^[1]	600	100	V
I _D	Continuous Drain Current	0.02	0.1	A
I _{DM}	Pulsed Drain Current ^[2]	0.08	0.4	
V _{GS}	Gate-to-Source Voltage	±20	±30	V
V _{ESD}	Gate to Source ESD ^[3]	1000	700	V
	Source to Gate ESD ^[3]	1000	700	V
P _D	Power Dissipation	1.5		W
T _L	Soldering Temperature Distance of 1.6mm from case for 10 seconds	300		°C
T _J and T _{STG}	Operating and Storage Temperature Range	-55 to 150		

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics

Symbol	Parameter	DME6010D	Unit
R _{θJA}	Thermal Resistance, Junction-to-Ambient	83.3	K/W

Electrical Characteristics

600V N-Channel Depletion MOSFET OFF Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
BV_{DSX}	Drain-to-Source Breakdown Voltage	600	--	--	V	$V_{GS} = -5\text{V}$, $I_D = 250\mu\text{A}$
$I_{D(OFF)}$	Drain-to-Source Leakage Current	--	--	0.1	μA	$V_{DS} = 600\text{V}$, $V_{GS} = -5\text{V}$
		--	--	10	μA	$V_{DS} = 600\text{V}$, $V_{GS} = -5\text{V}$ $T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Leakage Current	--	--	20	μA	$V_{GS} = +20\text{V}$, $V_{DS} = 0\text{V}$
		--	--	-20		$V_{GS} = -20\text{V}$, $V_{DS} = 0\text{V}$

ON Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
I_{DSS}	Saturated Drain-to-Source Current	5	--	25	mA	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	500	700	Ω	$V_{GS} = 0\text{V}$, $I_D = 3\text{mA}$ [4]
$V_{GS(OFF)}$	Gate-to-Source Cut-off Voltage	-1.5	--	-3.3	V	$V_{DS} = 3\text{V}$, $I_D = 8\mu\text{A}$
gfs	Forward Transconductance	--	15.4	--	mS	$V_{DS} = 10\text{V}$, $I_D = 5\text{mA}$

Dynamic Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
C_{ISS}	Input Capacitance	--	12.3	--	pF	$V_{GS} = -5\text{V}$ $V_{DS} = 25\text{V}$ $f = 1.0\text{MHz}$
C_{OSS}	Output Capacitance	--	2.6	--		
C_{RSS}	Reverse Transfer Capacitance	--	1.8	--		
Q_G	Total Gate Charge	--	1.55	--	nC	$V_{GS} = -5\text{V} \sim 5\text{V}$ $V_{DS} = 300\text{V}$, $I_D = 7\text{mA}$
Q_{GS}	Gate-to-Source Charge	--	0.12	--		
Q_{GD}	Gate-to-Drain (Miller) Charge	--	0.56	--		

Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$t_{d(on)}$	Turn-on Delay Time	--	4	--	ns	$V_{GS} = -5\text{V} \sim 5\text{V}$ $V_{DD} = 300\text{V}$, $I_D = 7\text{mA}$ $R_G = 20\Omega$
t_{rise}	Rise Time	--	9	--		
$t_{d(off)}$	Turn-off Delay Time	--	14	--		
t_{fall}	Fall Time	--	84	--		

Source-Drain Diode Characteristics

 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
V_{SD}	Diode Forward Voltage	--	--	1.2	V	$I_{SD} = 3.0\text{mA}$, $V_{GS} = -10\text{V}$

100V N-Channel MOSFET
OFF Characteristics
 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
BV_{DSX}	Drain-to-Source Breakdown Voltage	100	--	--	V	$V_{GS} = -30\text{V}$, $I_D = 250\mu\text{A}$
$I_{D(OFF)}$	Drain-to-Source Leakage Current	--	--	10	μA	$V_{DS} = 100\text{V}$, $V_{GS} = -30\text{V}$
I_{GSS}	Gate-to-Source Leakage Current	--	--	20	μA	$V_{GS} = +30\text{V}$, $V_{DS} = 0\text{V}$
		--	--	-20		$V_{GS} = -30\text{V}$, $V_{DS} = 0\text{V}$

ON Characteristics
 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
I_{DSS}	Saturated Drain-to-Source Current	100	--	--	mA	$V_{GS} = 0\text{V}$, $V_{DS} = 25\text{V}$
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	--	30	Ω	$V_{GS} = 0\text{V}$, $I_D = 100\text{mA}$ ^[4]
$V_{GS(OFF)}$	Gate-to-Source Cut-off Voltage	--	--	-27	V	$V_{DS} = 9\text{V}$, $I_D = 8\mu\text{A}$
V_{CL}	Source-to-Gate Clamp Voltage	11.5	--	--	V	$V_{DS} = 9\text{V}$, $I_D = 5\text{mA}$

Source-Drain Diode Characteristics
 $T_A = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min	Typ.	Max.	Units	Test Conditions
V_{SD}	Diode Forward Voltage	--	--	1.2	V	$I_{SD} = 100\text{mA}$, $V_{GS} = -30\text{V}$

NOTE:

[1] $T_J = +25^\circ\text{C}$ to $+150^\circ\text{C}$

[2] Repetitive rating, pulse width limited by maximum junction temperature.

[3] The test is based on JEDEC EIA/JESD22-A114 (HBM).

[4] Pulse width $\leq 380\mu\text{s}$; duty cycle $\leq 2\%$.

Typical Characteristics

600V N-Channel Depletion MOSFET

Figure 1. Maximum Power Dissipation vs. Case Temperature

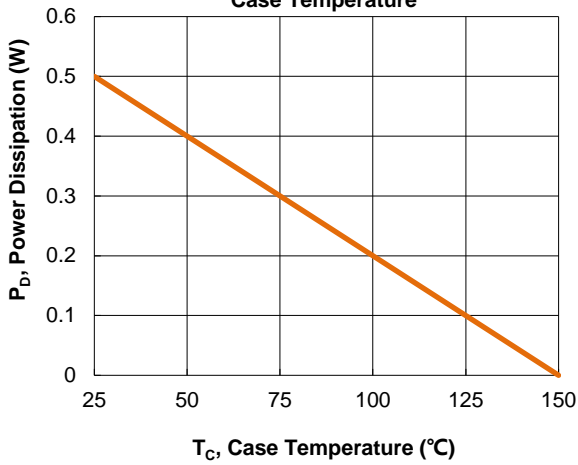


Figure 2. Maximum Continuous Drain Current vs Case Temperature

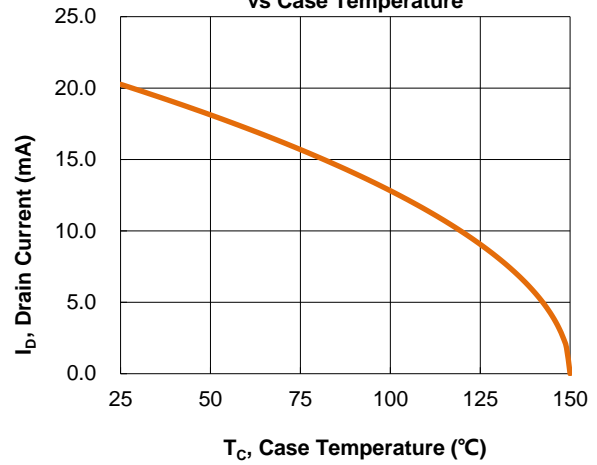


Figure 3. Typical Output Characteristics

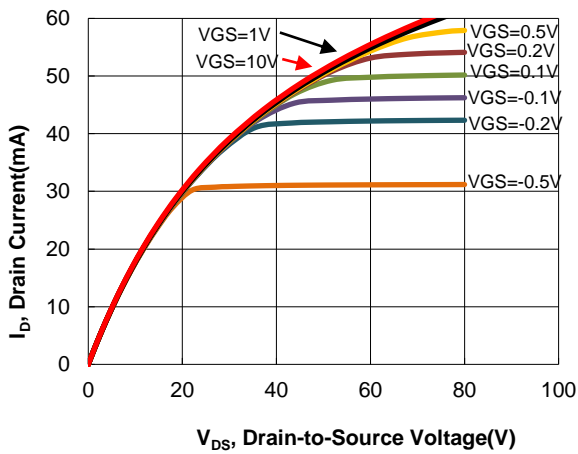


Figure 4. Typical Transfer Characteristics

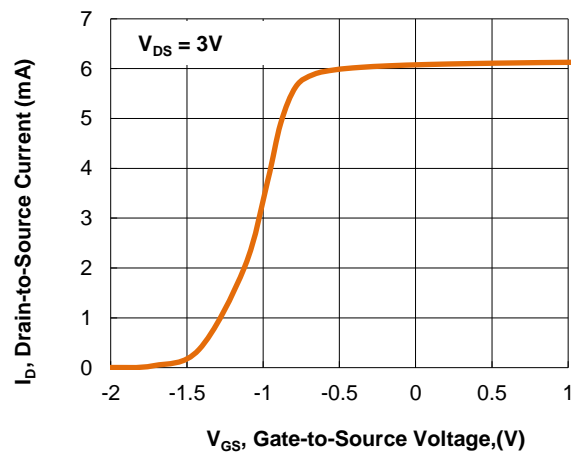


Figure 5. Typical Capacitance vs. Drain-to-Source Voltage

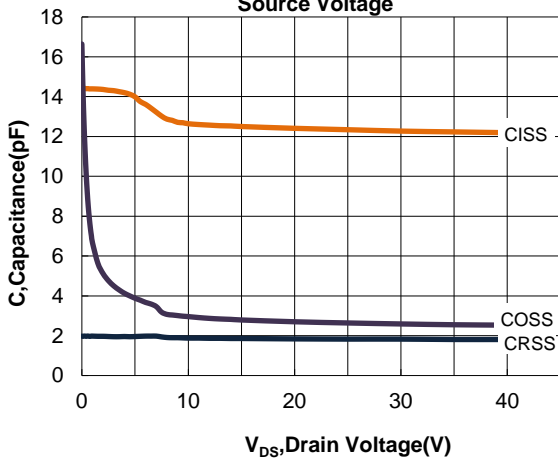
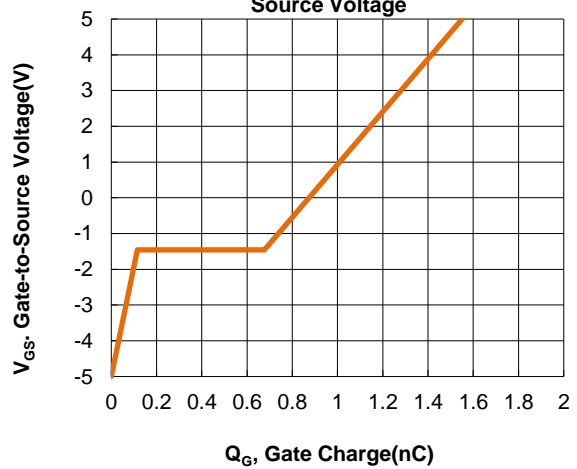


Figure 6. Typical Gate Charge vs. Gate-to-Source Voltage



100V N-Channel MOSFET

100V N-Channel MOSFET is an ultra-high threshold voltage depletion mode MOS device. A stable output voltage source or current source is implemented by using the sub-threshold characteristics of the device. Its basic application is shown as Figure 7:

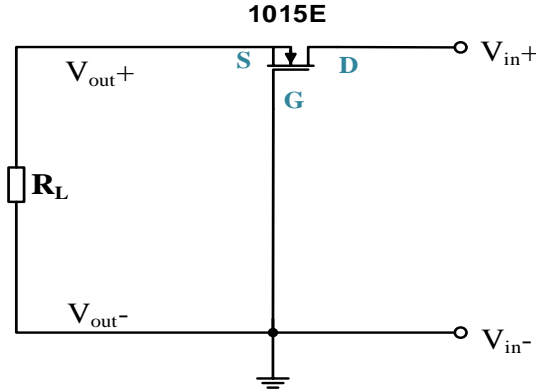


Figure7. Drain Current I_D is decided by Load Resistance

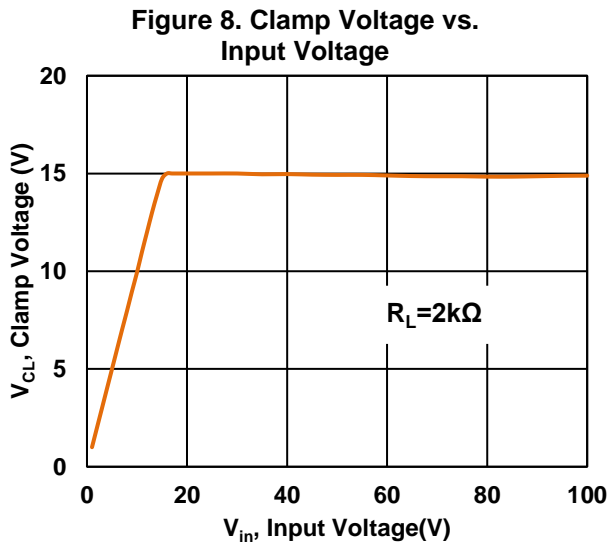


Figure 8. Clamp Voltage vs. Input Voltage

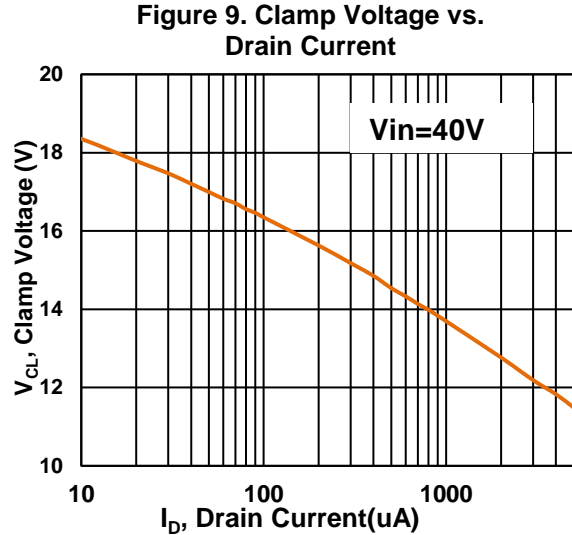


Figure 9. Clamp Voltage vs. Drain Current

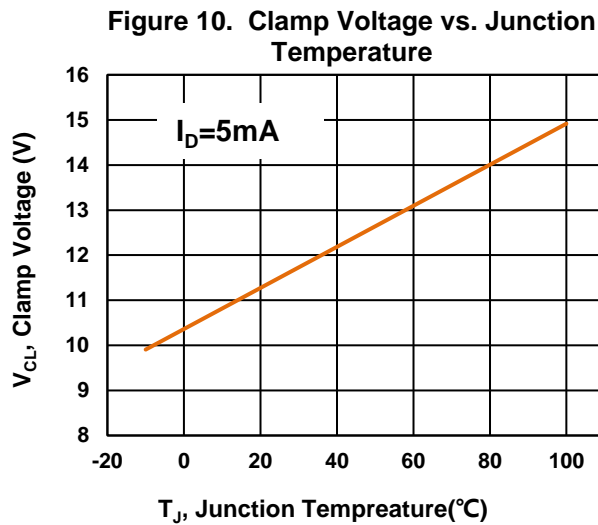


Figure 10. Clamp Voltage vs. Junction Temperature

Typical Application

DME6010D integrates a 600V depletion mode MOSFET as a startup device, and a 100V depletion mode MOSFET with patented UltraVt[®], which will provide stable and safe voltage for load as a non-isolated high voltage regulator. DME6010D is used in PD charger or QC charger for the cost down and space saving purpose. The circuit is as follows:

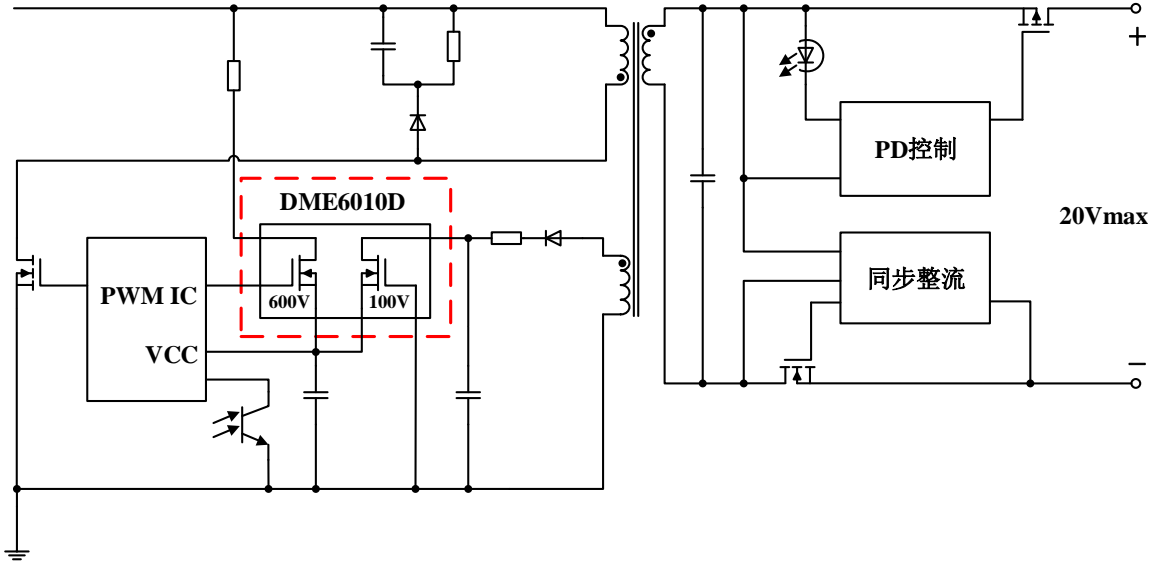
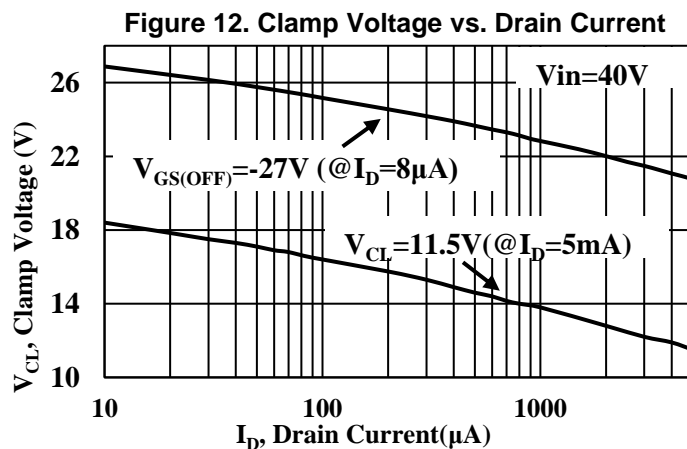


Figure 11. The circuit with DME6010D

In Figure 11, 600V MOSFET is used for PWM IC startup and 100V MOSFET is used as a high voltage linear regulator to make the PWM IC power supply circuit more simplified.

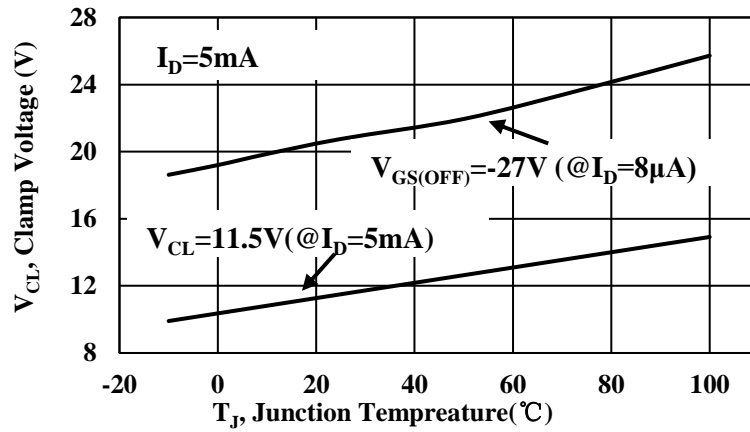
At room temperature and under 2~4mA working current (most IC's working current), the output voltage of 100V MOSFET is between 12~22V.

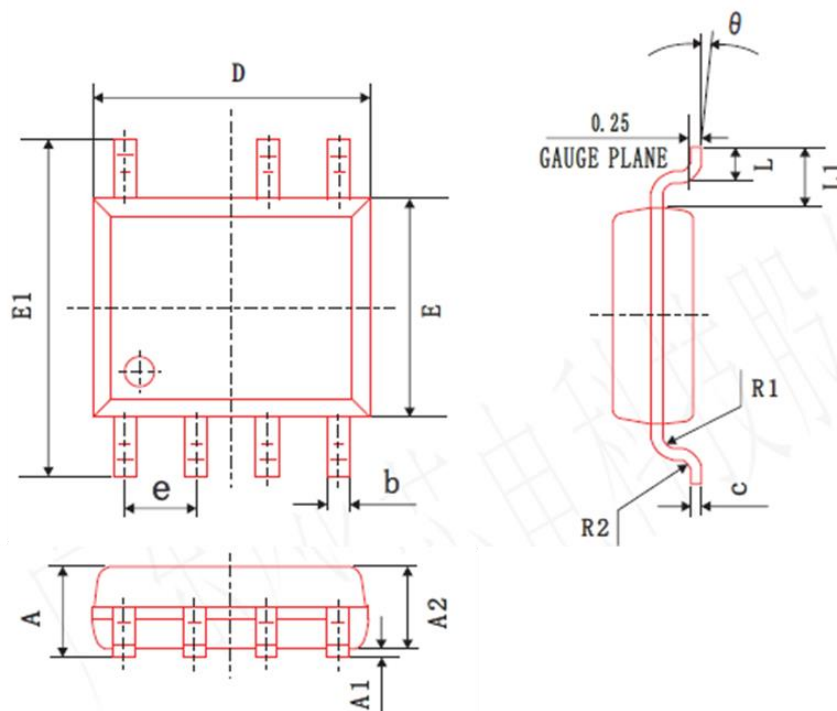
Due to strict design and process control, the parameters of 100V MOSFET have good consistency, but there are still some $V_{GS(OFF)}$ parameter distribution range, so we strictly control the final testing standard, the upper limit is $|V_{GS(OFF)}| = 27V$ (under normal temperature $I_D = 8\mu A$), the lower limit is $V_{CL} = 11.5V$ of clamping voltage (under room temperature $I_D = 5mA$), so as to ensure under normal working condition and the working current $8\mu A \leq I_D \leq 5mA$, the clamping voltage: $11.5V \leq V_{CL} \leq 27V$. Figure 13 shows the clamping voltage V_{CL} lower limit of 11.5V and the threshold voltage $V_{GS(OFF)}$ upper limit of $V_{GS(OFF)} = -27V$, and the clamping working voltage distribution when the working current does not exceed 5mA.



The clamping voltage will also change with the temperature. When the working temperature increases, the clamping voltage will increase; when the working temperature decreases, the clamping voltage will also decrease. The relationship between clamping voltage and junction temperature is shown in Figure 13:

Figure 13. Clamp Voltage vs. Junction Temperature



Package Dimensions
SOP-7


SYMBOL	MIN	NOM	MAX
A	1.40	1.60	1.80
A 1	0.05	0.15	0.25
A 2	1.35	1.45	1.55
b	0.30	0.40	0.50
C	0.153	0.203	0.253
D	4.80	4.90	5.00
E	3.80	3.90	4.00
E 1	5.80	6.00	6.20
L	0.45	0.70	1.00
θ	2°	4°	6°
L 1	1.04 REF		
e	1.27 BSC		
R 1	0.07 TYP		
R 2	0.07 TYP		

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